Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/915,554	LEE ET AL.
Examiner	Art Unit

2618

JOHN J. LEE

SEARCHED					
Class	Subclass	Date	Examiner		
455	517-521 515,434 11.1,452.1	3/10/2008	J.L		
455	3.01,3.03	3/10/2008	J.L		
455	502,512	3/10/2008	J.L		
455	510,41.2	3/10/2008	J.L		
370	449,346	3/10/2008	J.L		
370	343,344	3/10/2008	J.L		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
455	517-521	3/28/2008	J.L	
455	3.01,512	3/28/2008	J.L	
455	502,41.2	3/28/2008	J.L	
search,in	ub text terference arch	3/28/2008	J.L	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
EAST	3/10/2008	J.L		
Consulted with Willington Chin (370), Andy Lee (370) Hyun Soon (370)	3/10/2008	J.L		
Consulted with Nguyen Lee (455) for strong suggestion, George Eng (455), Meless Zewdu (455)	3/25/2008	J.L		